

Abstract Submitted
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Magnetic Excitations in Thin Film Ba₂IrO₄ and Sr₂IrO₄ Probed by Resonant Inelastic X-ray Scattering J.P. CLANCY, A. LUPASCU, H. GRE-TARSSON, University of Toronto, M.H. UPTON, J. KIM, Z. ISLAM, Argonne National Laboratory, M. UCHIDA, D.G. SCHLOM, K.M. SHEN, Cornell University, J. NICHOLS, J. TERZIC, G. CAO, S.S.A. SEO, University of Kentucky, V.M. KATUKURI, L. HOZOI, J. VAN DEN BRINK, IFW Dresden, H. STOLL, Stuttgart University, Y.-J. KIM, University of Toronto — We have performed resonant inelastic x-ray scattering (RIXS) measurements on epitaxial thin film samples of the layered perovskite iridates Ba₂IrO₄ and Sr₂IrO₄. These materials display a novel Jeff = 1/2 Mott insulating ground state driven by strong 5d spin-orbit coupling effects. By studying 10 to 50 nm thin film samples grown on a variety of different substrates (GSO, STO, LSAT), we have investigated the impact of applied tensile/compressive strain on the characteristic magnetic and electronic excitations of these materials. Unlike other perturbations, such as doping or applied magnetic field, we find that applied strain does not alter the magnetic structure of Ba₂IrO₄ or Sr₂IrO₄. However, strain does affect the magnetic energy scales of these systems, providing a means of tuning both the ordering temperature (T_n) and the magnetic exchange interactions (J). In addition, we show that the dispersion of the low-lying magnon and spin-orbit exciton modes is renormalized by strain-induced structural changes.

James Clancy
Univ of Toronto

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